AVL Supermicro server platform Memory Module Qualification Test

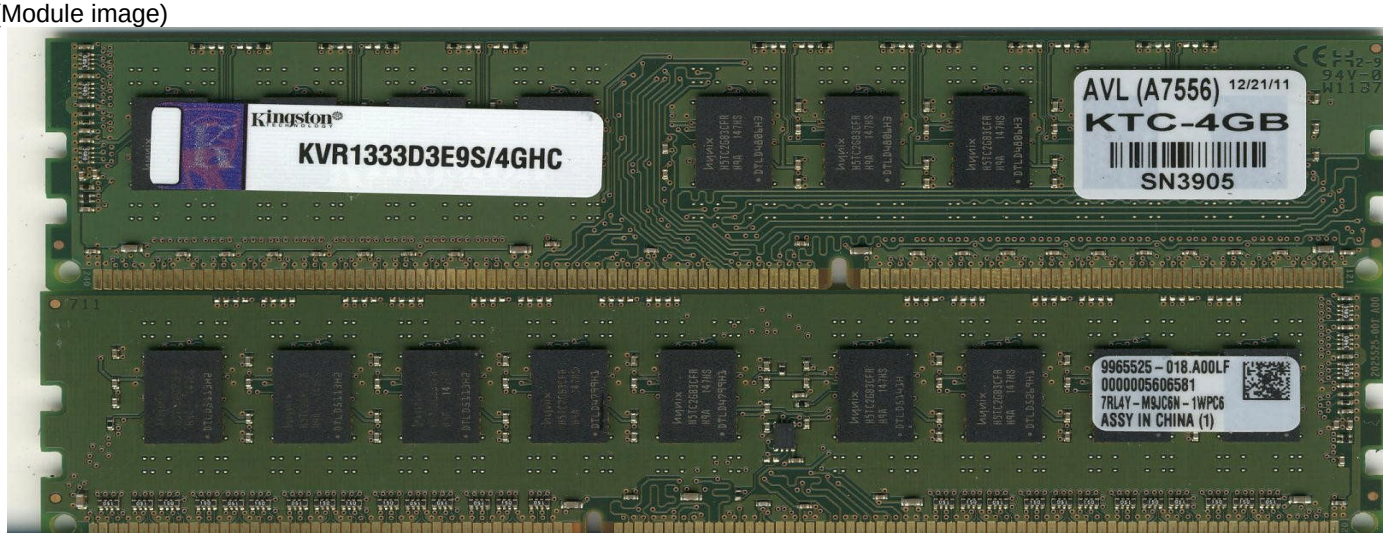
Intel X5650(WSM) x 2, Intel 5520 (Tylersburg), Rev C2	Test Results	Pass
PN: KVR1333D3E9S/4GHC (4GB / UDIMM ECC / ECC) On: X8DT3 Rev.2.00		

Module Information

RP77D3x-106-KI-SQ-SMC-V1 — Rev 01/07/2011

AVL WorkOrder #	WC2600	AVL A#	7556
Start Date	1/12/2012	End Date	1/18/2012
Tested By		Van N	
Module Manufacturer		Kingston	
Module Part Number		KVR1333D3E9S/4GHC	
Module BOM Number		9965525-018.A00LF	
Module Capacity / Memory Type / ECC		4GB / UDIMM ECC / ECC	
Module Configuration (Width, # of devices, # of Ranks)		512Mx72 /18 Devices / 2 Ranks	
Speed Tested (Data rate of Mbps, CL-tRP-tRCD)		DDR3-1333 /9-9-9	
DRAM Device Vendor		Hynix	
DRAM Device Part Number / Date code		H5TC2G83CFR-H9A	1147
DRAM Die Revision / Process Technology (nm)		C	
DRAM Device Config (Density / Width)		2Gbit / x8	
Thermal Sensor Device Vendor / Part Number / Revision			
Register Device Vendor / Part Number / Revision			

(Module image)



Platform System Information

Motherboard Info (Model# & MB Revision & MB S/N & AVL S/N)	X8DT3	2.00	OM06S30241	SK4377
BIOS Revision / BIOS Date / MRC Rev.	2.0a	9/14/2010	2.11	
CPU / Speed	Intel X5650(WSM) x 2		2.66GHz	
Chipset info (Stepping)	Intel 5520 (Tylersburg), Rev C2			

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PN: KVR1333D3E9S/4GHC (4GB / UDIMM ECC / ECC) On: X8DT3 Rev.2.00

Test Results:	PASS
Commetnts:	

AVL Memory Module Qual Test Results Summary

Test # and name	Test Description	Specs	Test Results	Comments
1. Latest BIOS Upgrade & Configuration	Download / Upgrade latest BIOS & record size and speed detection	Per test platform, DIMM & config spec	**Done**	Record memory size & speed at each test only
2. SPD Check	Memory module SPD content check for JEDEC compliance	JEDEC	**Pass**	Use proprietary tools
3. Sisoftware Sandra Benchmark	Run Windows based diags & utility software @50°C - DIMM max loading.	1 loop per config	**Done**	Full load per spec
4. Passmark Burn-In		6 Hour per config	**Pass**	Full load per spec
5a. Stress Application Test	Run Linux based diags & utility software @50°C - DIMM max loading.	8 Hour per config	**Pass**	Full load per spec
5b. Stream Benchmark Test		5 loop per config	**Done**	Full load per spec
5c. Reset Cycle		500 loop per config	**Pass**	Full load per spec
6a. Functional Stress Test (Corner 1a)	Run RST Premium @50°C - DIMM max loading.	8 Hour or 2+ Loops per config	**Pass**	Full load per spec
6b. Functional Stress Test (Corner 1b)*	Run RST Premium @55°C - DIMM loading depends on @speed configuration	8 Hour or 2+ Loops per config	**N/A**	Per platform memory speed configuration table if different (run @Max module speed)
7. Functional Stress Test (Corner 2)	Run RST Premium @0°C DIMM max loading	8 Hour or 2+ Loops per config	**N/A**	Full load per spec

Note: All test under IMC Vdd=Nom, Vref=Vddnom/2

* Corner 1b test is not required if Corner 1A already covers max module speed.